

<b>Notice of References Cited</b>	Application/Control No. 10/769,240		Applicant(s)/Patent Under Reexamination LIN ET AL.	
	Examiner AMAL ZENATI		Art Unit 2614	Page 1 of 1

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*	C	US-4,896,358	01-1990	Bahler et al.	704/257
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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